Compound Semiconductor Materials EU TC Chapter

Meeting Summary and Minutes

April 9, 2019

Nurnburg, Germany

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Arnd Weber (SiCrystal)
SEMI Staff: James Amano

Company	*Last*	*First*	*Company*	*Last*	*First*
Si Crystal	Weber	Arnd			
Munich University	Alt	Hans Christian			
Freiberger	Kretzer	Ulrich			

Table 2 Leadership Changes

WG/TF/SC/TC Name	*Previous Leader*	*New Leader*
None		

Table 3 Committee Structure Changes

Previous WG/TF/SC Name	*New WG/TF/SC Name or Status Change*
None	

Table 4 Ballot Results

Document #	*Document Title*	*Committee Action*
None		

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

#	*Type*	*SC/TF/WG*	*Details*
None			

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Type	SC/TF/WG	Details
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:
http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF

Table 7 Authorized Ballots

#	When	TF	Details
6474	Cycle 6-2019	M82 Revision TF	Revision to SEMI M82, Test Method for the Carbon Acceptor Concentration in Semi-Insulating Gallium Arsenide Single Crystals by Infrared Absorption Spectroscopy
6546	Cycle 6-2019	M83 Revision TF	Revision to SEMI M83, Test Method for Determination of Dislocation Etch Pit Density in Monocrystals of III-V Compound Semiconductors

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
None			

Table 9 SNARF(s) Abolished

#	TF	Title
None		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
None	

Table 11 New Action Items

Item #	Assigned to	Details
CSM-0419-1	Hans-Christian Alt	Submit revision to M82 to Kevin Nguyen in time for Cycle 6 or 7
CSM-0419-2	Ulrich Kretzer	Submit revision to M83 to Kevin Nguyen in time for Cycle 6 or 7

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
CSM-1118-1	Arnd Weber	Determine date for Spring 2019 EU CSM TC Chapter meeting and inform SEMI Staff

1 Welcome, Reminders, and Introductions

Arnd Weber called the meeting to order at 13:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion:	Approve minutes from SEMICON Europa 2018 mtg
By / 2nd:	HC Alt/Ulrich Kretzer
Discussion:	None
Vote:	3-0

Attachment: EU CSM Europa 2018 v2

3 Liaison Reports

3.1 *Compound Semiconductor Materials North America TC Chapter*

James Amano reported. Of note:

- Next Meeting
    - In conjunction with CS Mantech
        - May 9
        - Austin, TX
- TF Updates
- GaN TF
- Document 4979A (New Standard: Specification for Polished Monocrystalline C-Plane Gallium Nitride Wafers) published as SEMI M86-0915.
    - TF was disbanded
- Silicon Carbide TF
    - Liaison with Europe TC Chapter

3.2 *Compound Semiconductor Materials TC Chapter Japan*

James Amano reported that the Japan Chapter had not recently met. Individual Japan members, however, are active in global activities

4 Ballot Review

None

5 Subcommittee and Task Force Reports

5.1 *M82 TF*

Hans Christian Alt reported for the Task Force. The revision to M82, TEST METHOD FOR THE CARBON ACCEPTOR CONCENTRATION IN SEMI-INSULATING GALLIUM ARSENIDE SINGLE CRYSTALS BY INFRARED ABSORPTION SPECTROSCOPY should be ready to ballot in time for adjudication at SEMICON Europa

Motion:	To issue ballot 6474 in Cycle 6 or 7 of 2019 for adjudication at SEMICON Europa
By / 2nd:	HC Alt/Ulrich Kretzer
Discussion:	None
Vote:	3-0

Action Item: Hans Christian Alt to submit ballot 6474 to SEMI staff in time for SEMICON Europa adjudication

5.2 *M83 Revision Task Force*

Ulrich Kretzer reported for the Task Force. The ballot to revise M83, Test Method for Determination of Dislocation Etch Pit Density in Monocrystals of III-V Compound Semiconductors, will be ready to ballot soon

Motion:	To ballot 6546 in Cycle 6 or 7 of 2019 for adjudication at SEMICON Europa
By / 2nd:	Ulrich Kretzer/HC Alt
Discussion:	None
Vote:	3-0

Action Item: Ulrich Kretzer to submit ballot 6474 to SEMI staff in time for SEMICON Europa adjudication

6 Old Business

None

7 New Business

None

8 Next Meeting and Adjournment

The next meeting is scheduled for SEMICON Europa 2019 in Munich. See http://www.semi.org/standards-events for the current list of events.